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"[Embedded - Microcontrollers](#)" refer to small, integrated circuits designed to perform specific tasks within larger systems. These microcontrollers are essentially compact computers on a single chip, containing a processor core, memory, and programmable input/output peripherals. They are called "embedded" because they are embedded within electronic devices to control various functions, rather than serving as standalone computers. Microcontrollers are crucial in modern electronics, providing the intelligence and control needed for a wide range of applications.

Applications of "[Embedded - Microcontrollers](#)"

Details

Product Status	Active
Core Processor	ARM® Cortex®-M4
Core Size	32-Bit Single-Core
Speed	120MHz
Connectivity	I²C, SPI, UART/USART
Peripherals	DMA, PWM, WDT
Number of I/O	70
Program Memory Size	512KB (512K x 8)
Program Memory Type	FLASH
EEPROM Size	-
RAM Size	96K x 8
Voltage - Supply (Vcc/Vdd)	1.71V ~ 3.6V
Data Converters	A/D 2x16b; D/A 1x12b
Oscillator Type	Internal
Operating Temperature	-40°C ~ 105°C (TA)
Mounting Type	Surface Mount
Package / Case	100-LQFP
Supplier Device Package	100-LQFP (14x14)
Purchase URL	https://www.e-xfl.com/product-detail/nxp-semiconductors/mkv31f512vll12

Table 2. V_{DD} supply LVD and POR operating requirements (continued)

Symbol	Description	Min.	Typ.	Max.	Unit	Notes
V _{HYSH}	Low-voltage inhibit reset/recover hysteresis — high range	—	80	—	mV	
V _{LVDL}	Falling low-voltage detect threshold — low range (LVDV=00)	1.54	1.60	1.66	V	
V _{LVW1L}	Low-voltage warning thresholds — low range					1
V _{LVW2L}	• Level 1 falling (LVWV=00)	1.74	1.80	1.86	V	
V _{LVW3L}	• Level 2 falling (LVWV=01)	1.84	1.90	1.96	V	
V _{LVW4L}	• Level 3 falling (LVWV=10)	1.94	2.00	2.06	V	
V _{LVW4L}	• Level 4 falling (LVWV=11)	2.04	2.10	2.16	V	
V _{HYSL}	Low-voltage inhibit reset/recover hysteresis — low range	—	60	—	mV	
V _{BG}	Bandgap voltage reference	0.97	1.00	1.03	V	
t _{LPO}	Internal low power oscillator period — factory trimmed	900	1000	1100	μs	

1. Rising threshold is the sum of falling threshold and hysteresis voltage

2.2.3 Voltage and current operating behaviors

Table 3. Voltage and current operating behaviors

Symbol	Description	Min.	Typ.	Max.	Unit	Notes
V _{OH}	Output high voltage — Normal drive pad except RESET_B 2.7 V ≤ V _{DD} ≤ 3.6 V, I _{OH} = -5 mA 1.71 V ≤ V _{DD} ≤ 2.7 V, I _{OH} = -2.5 mA	V _{DD} – 0.5 V _{DD} – 0.5	— —	— —	V V	1
V _{OH}	Output high voltage — High drive pad except RESET_B 2.7 V ≤ V _{DD} ≤ 3.6 V, I _{OH} = -20 mA 1.71 V ≤ V _{DD} ≤ 2.7 V, I _{OH} = -10 mA	V _{DD} – 0.5 V _{DD} – 0.5	— —	— —	V V	1
I _{OHT}	Output high current total for all ports	—	—	100	mA	
V _{OL}	Output low voltage — Normal drive pad except RESET_B 2.7 V ≤ V _{DD} ≤ 3.6 V, I _{OL} = 5 mA 1.71 V ≤ V _{DD} ≤ 2.7 V, I _{OL} = 2.5 mA	— —	— —	0.5 0.5	V V	1
V _{OL}	Output low voltage — High drive pad except RESET_B 2.7 V ≤ V _{DD} ≤ 3.6 V, I _{OL} = 20 mA 1.71 V ≤ V _{DD} ≤ 2.7 V, I _{OL} = 10 mA	— —	— —	0.5 0.5	V V	1
V _{OL}	Output low voltage — RESET_B					

Table continues on the next page...

Table 3. Voltage and current operating behaviors (continued)

Symbol	Description	Min.	Typ.	Max.	Unit	Notes
	2.7 V ≤ V_{DD} ≤ 3.6 V, $I_{OL} = 3 \text{ mA}$	—	—	0.5	V	
	1.71 V ≤ V_{DD} ≤ 2.7 V, $I_{OL} = 1.5 \text{ mA}$	—	—	0.5	V	
I_{OLT}	Output low current total for all ports	—	—	100	mA	
I_{IN}	Input leakage current (per pin) for full temperature range					
	All pins other than high drive port pins	—	0.002	0.5	μA	1, 2
	High drive port pins	—	0.004	0.5	μA	
I_{IN}	Input leakage current (total all pins) for full temperature range	—	—	1.0	μA	2
R_{PU}	Internal pullup resistors	20	—	50	$\text{k}\Omega$	3
R_{PD}	Internal pulldown resistors	20	—	50	$\text{k}\Omega$	4

1. PTB0, PTB1, PTC3, PTC4, PTD4, PTD5, PTD6, and PTD7 I/O have both high drive and normal drive capability selected by the associated PTx_PCRn[DSE] control bit. All other GPIOs are normal drive only.
2. Measured at $V_{DD}=3.6\text{V}$
3. Measured at V_{DD} supply voltage = V_{DD} min and $V_{in} = V_{SS}$
4. Measured at V_{DD} supply voltage = V_{DD} min and $V_{in} = V_{DD}$

2.2.4 Power mode transition operating behaviors

All specifications except t_{POR} , and $VLLSx \rightarrow \text{RUN}$ recovery times in the following table assume this clock configuration:

- CPU and system clocks = 80 MHz
- Bus clock = 40 MHz
- FlexBus clock = 20 MHz
- Flash clock = 20 MHz
- MCG mode: FEI

Table 4. Power mode transition operating behaviors

Symbol	Description	Min.	Typ.	Max.	Unit	Notes
t_{POR}	After a POR event, amount of time from the point V_{DD} reaches 1.71 V to execution of the first instruction across the operating temperature range of the chip.	—	—	300	μs	1
	• $VLLS0 \rightarrow \text{RUN}$	—	—	140	μs	
	• $VLLS1 \rightarrow \text{RUN}$	—	—	140	μs	

Table continues on the next page...

Table 4. Power mode transition operating behaviors (continued)

Symbol	Description	Min.	Typ.	Max.	Unit	Notes
	• VLLS2 → RUN	—	—	80	μs	
	• VLLS3 → RUN	—	—	80	μs	
	• LLS2 → RUN	—	—	6	μs	
	• LLS3 → RUN	—	—	6	μs	
	• VLPS → RUN	—	—	5.7	μs	
	• STOP → RUN	—	—	5.7	μs	

1. Normal boot (FTFA_OPT[LPBOOT]=1)

2.2.5 Power consumption operating behaviors

The current parameters in the table below are derived from code executing a while(1) loop from flash, unless otherwise noted.

The IDD typical values represent the statistical mean at 25°C, and the IDD maximum values for RUN, WAIT, VLPR, and VLPW represent data collected at 125°C junction temperature unless otherwise noted. The maximum values represent characterized results equivalent to the mean plus three times the standard deviation (mean + 3 sigma).

Table 5. Power consumption operating behaviors

Symbol	Description	Min.	Typ.	Max.	Unit	Notes
I _{DDA}	Analog supply current	—	—	See note	mA	1
I _{DD_HSRUN}	High Speed Run mode current - all peripheral clocks disabled, CoreMark benchmark code executing from flash @ 1.8V	—	28.0	29.33	mA	2, 3, 4
	@ 3.0V	—	28.0	29.33	mA	
I _{DD_HSRUN}	High Speed Run mode current - all peripheral clocks disabled, code executing from flash @ 1.8V	—	25.6	26.93	mA	2
	@ 3.0V	—	25.7	27.03	mA	
I _{DD_HSRUN}	High Speed Run mode current — all peripheral clocks enabled, code executing from flash					

Table continues on the next page...

Table 5. Power consumption operating behaviors (continued)

Symbol	Description	Min.	Typ.	Max.	Unit	Notes
	@ 1.8V @ 3.0V	— —	35.5 35.6	36.83 36.93	mA mA	5
I _{DD_RUN}	Run mode current in Compute operation — CoreMark benchmark code executing from flash @ 1.8V @ 3.0V	— —	17.5 17.5	18.83 18.83	mA mA	3, 4, 6
I _{DD_RUN}	Run mode current in Compute operation — code executing from flash @ 1.8V @ 3.0V	— —	15.10 15.10	17.10 17.33	mA mA	6
I _{DD_RUN}	Run mode current — all peripheral clocks disabled, code executing from flash @ 1.8V @ 3.0V	— —	16.6 16.8	17.93 18.13	mA mA	7
I _{DD_RUN}	Run mode current — all peripheral clocks enabled, code executing from flash @ 1.8V @ 3.0V • @ 25°C • @ 70°C • @ 85°C • @ 105°C	— — — — — —	22.8 22.9 23.1 23.5 23.8	24.13 24.23 24.43 24.83 25.13	mA mA mA mA mA	8
I _{DD_RUN}	Run mode current — Compute operation, code executing from flash @ 1.8V @ 3.0V • @ 25°C • @ 70°C • @ 85°C • @ 105°C	— — — — — —	15.1 15.1 15.4 15.6 16.0	16.43 16.43 16.73 16.93 17.33	mA mA mA mA mA	9
I _{DD_WAIT}	Wait mode high frequency current at 3.0 V — all peripheral clocks disabled	—	9.3	10.63	mA	7
I _{DD_WAIT}	Wait mode reduced frequency current at 3.0 V — all peripheral clocks disabled	—	5.4	6.73	mA	10
I _{DD_VLPR}	Very-low-power run mode current in Compute operation — CoreMark benchmark code executing from flash @ 1.8V @ 3.0V	— —	0.88 0.89	1.02 1.03	mA mA	3, 4, 11

Table continues on the next page...

Table 5. Power consumption operating behaviors (continued)

Symbol	Description	Min.	Typ.	Max.	Unit	Notes
I _{DD_VLLS1}	Very low-leakage stop mode 1 current at 3.0 V @ -40°C to 25°C @ 70°C @ 85°C @ 105°C	—	0.73	1.42	µA	
		—	1.8	3.90	µA	
		—	3.0	5.25	µA	
		—	5.9	10.80	µA	
I _{DD_VLLS0}	Very low-leakage stop mode 0 current at 3.0 V with POR detect circuit enabled @ -40°C to 25°C @ 70°C @ 85°C @ 105°C	—	0.43	0.55	µA	
		—	1.4	2.45	µA	
		—	2.6	4.00	µA	
		—	5.4	9.30	µA	
I _{DD_VLLS0}	Very low-leakage stop mode 0 current at 3.0 V with POR detect circuit disabled @ -40°C to 25°C @ 70°C @ 85°C @ 105°C	—	0.14	0.24	µA	
		—	1.1	2.15	µA	
		—	2.3	3.85	µA	
		—	5.1	9.00	µA	

1. The analog supply current is the sum of the active or disabled current for each of the analog modules on the device. See each module's specification for its supply current.
2. 120MHz core and system clock, 60MHz bus clock, 24MHz FlexBus clock, and 24MHz flash clock. MCG configured for PEE mode. All peripheral clocks disabled.
3. Cache on and prefetch on, low compiler optimization.
4. Coremark benchmark compiled using IAR 7.2 with optimization level low.
5. 120MHz core and system clock, 60MHz bus clock, 24MHz FlexBus clock, and 24MHz flash clock. MCG configured for PEE mode. All peripheral clocks enabled.
6. 80 MHz core and system clock, 40 MHz bus clock, and 26.67 MHz flash clock. MCG configured for PEE mode. Compute operation.
7. 80MHz core and system clock, 40MHz bus clock, 20MHz FlexBus clock, and 26.67MHz flash clock. MCG configured for FEI mode. All peripheral clocks disabled.
8. 80MHz core and system clock, 40MHz bus clock, 20MHz FlexBus clock, and 26.67MHz flash clock. MCG configured for FEI mode. All peripheral clocks enabled.
9. 80MHz core and system clock, 40MHz bus clock, and 26.67MHz flash clock. MCG configured for FEI mode. Compute operation.
10. 25MHz core and system clock, 25MHz bus clock, and 25MHz FlexBus and flash clock. MCG configured for FEI mode.
11. 4 MHz core, system, FlexBus, and bus clock and 1MHz flash clock. MCG configured for BLPE mode. Compute operation. Code executing from flash.
12. 4 MHz core, system, FlexBus, and bus clock and 1MHz flash clock. MCG configured for BLPE mode. All peripheral clocks disabled. Code executing from flash.
13. 4 MHz core, system, FlexBus, and bus clock and 1MHz flash clock. MCG configured for BLPE mode. All peripheral clocks enabled but peripherals are not in active operation. Code executing from flash.
14. 4 MHz core, system, FlexBus, and bus clock and 1MHz flash clock. MCG configured for BLPE mode. All peripheral clocks disabled.

General

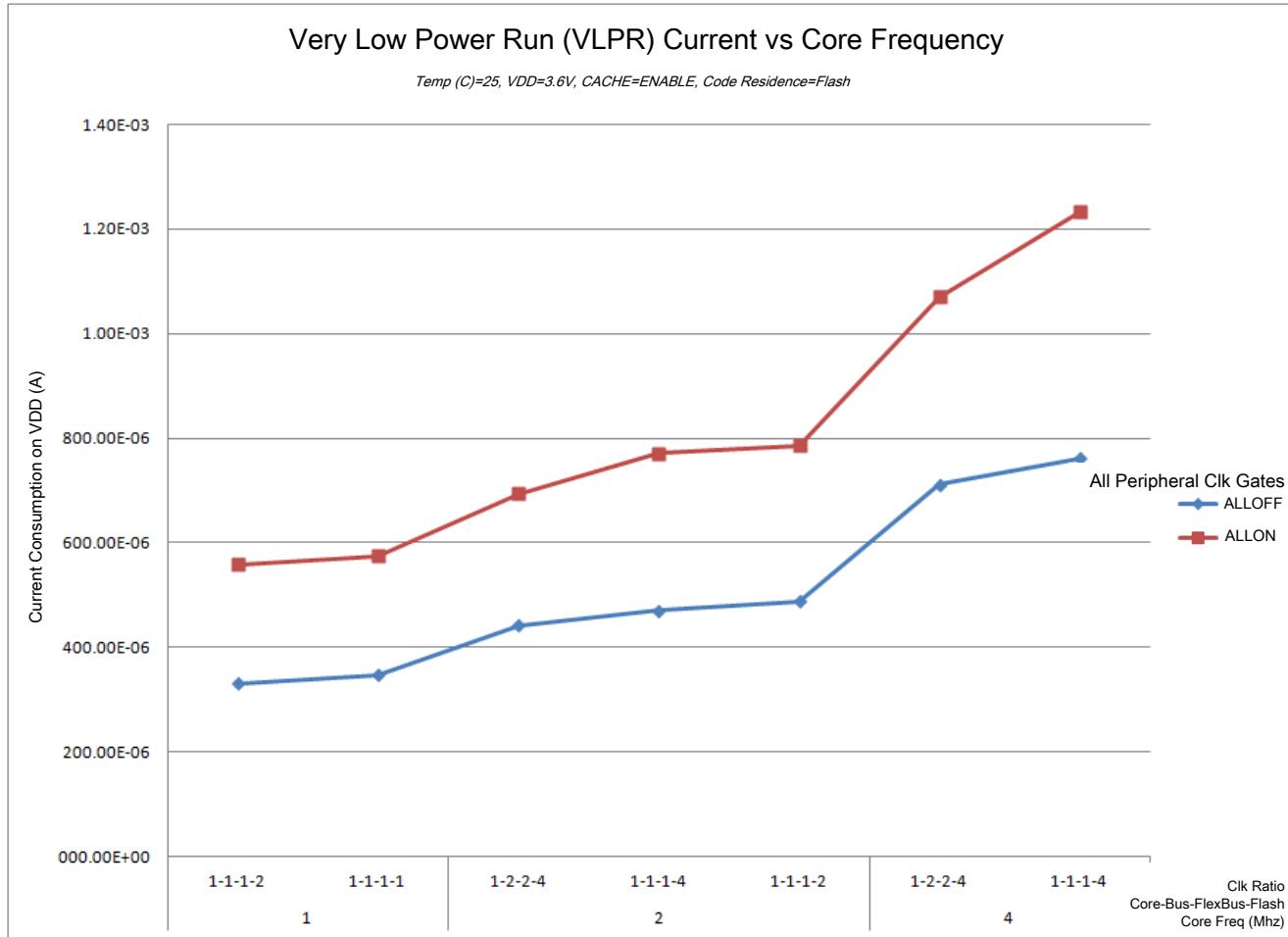


Figure 4. VLPR mode supply current vs. core frequency

2.2.6 EMC radiated emissions operating behaviors

Table 7. EMC radiated emissions operating behaviors for 64 LQFP package

Parameter	Conditions	Clocks	Frequency range	Level (Typ.)	Unit	Notes
V_{EME}	Device configuration, test conditions and EM testing per standard IEC 61967-2. Supply voltages: <ul style="list-style-type: none">• VDD = 3.3 V Temp = 25°C	FSYS = 120 MHz FBUS = 60 MHz External crystal = 8 MHz	150 kHz–50 MHz	14	dBuV	1, 2, 3
			50 MHz–150 MHz	23		
			150 MHz–500 MHz	23		
			500 MHz–1000 MHz	9		
			IEC level	L		4

1. Measurements were made per IEC 61967-2 while the device was running typical application code.
2. Measurements were performed on a similar 64LQFP device.
3. The reported emission level is the value of the maximum measured emission, rounded up to the next whole number, from among the measured orientations in each frequency range.

4. IEC Level Maximums: M \leq 18dBmV, L \leq 24dBmV, K \leq 30dBmV, I \leq 36dBmV, H \leq 42dBmV .

2.2.7 Designing with radiated emissions in mind

To find application notes that provide guidance on designing your system to minimize interference from radiated emissions:

1. Go to www.freescale.com.
2. Perform a keyword search for “EMC design.”

2.2.8 Capacitance attributes

Table 8. Capacitance attributes

Symbol	Description	Min.	Max.	Unit
C_{IN_A}	Input capacitance: analog pins	—	7	pF
C_{IN_D}	Input capacitance: digital pins	—	7	pF

2.3 Switching specifications

2.3.1 Device clock specifications

Table 9. Device clock specifications

Symbol	Description	Min.	Max.	Unit	Notes
High Speed run mode					
f_{SYS}	System and core clock	—	120	MHz	
f_{BUS}	Bus clock	—	60	MHz	
Normal run mode (and High Speed run mode unless otherwise specified above)					
f_{SYS}	System and core clock	—	80	MHz	
f_{BUS}	Bus clock	—	50	MHz	
FB_CLK	FlexBus clock	—	30	MHz	
f_{FLASH}	Flash clock	—	26.67	MHz	
f_{LPTMR}	LPTMR clock	—	25	MHz	
VLPR mode ¹					
f_{SYS}	System and core clock	—	4	MHz	
f_{BUS}	Bus clock	—	4	MHz	
FB_CLK	FlexBus clock	—	4	MHz	

Table continues on the next page...

Table 9. Device clock specifications (continued)

Symbol	Description	Min.	Max.	Unit	Notes
f_{FLASH}	Flash clock	—	1	MHz	
f_{ERCLK}	External reference clock	—	16	MHz	
f_{LPTMR_pin}	LPTMR clock	—	25	MHz	
f_{LPTMR_ERCLK}	LPTMR external reference clock	—	16	MHz	

1. The frequency limitations in VLPR mode here override any frequency specification listed in the timing specification for any other module.

2.3.2 General switching specifications

These general purpose specifications apply to all signals configured for GPIO, UART, and timers.

Table 10. General switching specifications

Symbol	Description	Min.	Max.	Unit	Notes
	GPIO pin interrupt pulse width (digital glitch filter disabled) — Synchronous path	1.5	—	Bus clock cycles	1, 2
	External RESET and NMI pin interrupt pulse width — Asynchronous path	100	—	ns	3
	GPIO pin interrupt pulse width (digital glitch filter disabled, passive filter disabled) — Asynchronous path	50	—	ns	4
	Mode select (EZP_CS) hold time after reset deassertion	2	—	Bus clock cycles	
	Port rise and fall time <ul style="list-style-type: none"> Slew disabled <ul style="list-style-type: none"> $1.71 \leq V_{DD} \leq 2.7V$ $2.7 \leq V_{DD} \leq 3.6V$ Slew enabled <ul style="list-style-type: none"> $1.71 \leq V_{DD} \leq 2.7V$ $2.7 \leq V_{DD} \leq 3.6V$ 	— — — —	10 5 30 16	ns ns ns ns	5

1. This is the minimum pulse width that is guaranteed to pass through the pin synchronization circuitry. Shorter pulses may or may not be recognized. In Stop, VLPS, LLS, and VLLSx modes, the synchronizer is bypassed so shorter pulses can be recognized in that case.
2. The greater of synchronous and asynchronous timing must be met.
3. These pins have a passive filter enabled on the inputs. This is the shortest pulse width that is guaranteed to be recognized.
4. These pins do not have a passive filter on the inputs. This is the shortest pulse width that is guaranteed to be recognized.
5. 25 pF load

Table 15. MCG specifications (continued)

Symbol	Description	Min.	Typ.	Max.	Unit	Notes
f_{loc_low}	Loss of external clock minimum frequency — RANGE = 00	$(3/5) \times f_{ints_t}$	—	—	kHz	
f_{loc_high}	Loss of external clock minimum frequency — RANGE = 01, 10, or 11	$(16/5) \times f_{ints_t}$	—	—	kHz	
FLL						
f_{fll_ref}	FLL reference frequency range	31.25	—	39.0625	kHz	
f_{dco}	DCO output frequency range	Low range (DRS=00) $640 \times f_{fll_ref}$	20	20.97	25	MHz
		Mid range (DRS=01) $1280 \times f_{fll_ref}$	40	41.94	50	MHz
		Mid-high range (DRS=10) $1920 \times f_{fll_ref}$	60	62.91	75	MHz
		High range (DRS=11) $2560 \times f_{fll_ref}$	80	83.89	100	MHz
$f_{dco_t_DMX3_2}$	DCO output frequency	Low range (DRS=00) $732 \times f_{fll_ref}$	—	23.99	—	MHz
		Mid range (DRS=01) $1464 \times f_{fll_ref}$	—	47.97	—	MHz
		Mid-high range (DRS=10) $2197 \times f_{fll_ref}$	—	71.99	—	MHz
		High range (DRS=11) $2929 \times f_{fll_ref}$	—	95.98	—	MHz
J_{cyc_fll}	FLL period jitter		—	—	—	ps
	• $f_{VCO} = 48$ MHz		—	180	—	
	• $f_{VCO} = 98$ MHz		—	150	—	
$t_{fll_acquire}$	FLL target frequency acquisition time	—	—	1	ms	7
PLL						
f_{vco}	VCO operating frequency	48.0	—	120	MHz	
I_{pll}	PLL operating current • PLL @ 96 MHz ($f_{osc_hi_1} = 8$ MHz, $f_{pll_ref} = 2$ MHz, VDIV multiplier = 48)	—	1060	—	μA	8
I_{pll}	PLL operating current • PLL @ 48 MHz ($f_{osc_hi_1} = 8$ MHz, $f_{pll_ref} = 2$ MHz, VDIV multiplier = 24)	—	600	—	μA	8
f_{pll_ref}	PLL reference frequency range	2.0	—	4.0	MHz	
J_{cyc_pll}	PLL period jitter (RMS)		—	120	—	ps
	• $f_{VCO} = 48$ MHz		—	75	—	ps
J_{acc_pll}	PLL accumulated jitter over 1 μs (RMS)					9

Table continues on the next page...

3.4.2 EzPort switching specifications

Table 23. EzPort switching specifications

Num	Description	Min.	Max.	Unit
	Operating voltage	1.71	3.6	V
EP1	EZP_CK frequency of operation (all commands except READ)	—	$f_{SYS}/2$	MHz
EP1a	EZP_CK frequency of operation (READ command)	—	$f_{SYS}/8$	MHz
EP2	EZP_CS negation to next EZP_CS assertion	$2 \times t_{EZP_CK}$	—	ns
EP3	EZP_CS input valid to EZP_CK high (setup)	5	—	ns
EP4	EZP_CK high to EZP_CS input invalid (hold)	5	—	ns
EP5	EZP_D input valid to EZP_CK high (setup)	2	—	ns
EP6	EZP_CK high to EZP_D input invalid (hold)	5	—	ns
EP7	EZP_CK low to EZP_Q output valid	—	25	ns
EP8	EZP_CK low to EZP_Q output invalid (hold)	0	—	ns
EP9	EZP_CS negation to EZP_Q tri-state	—	12	ns

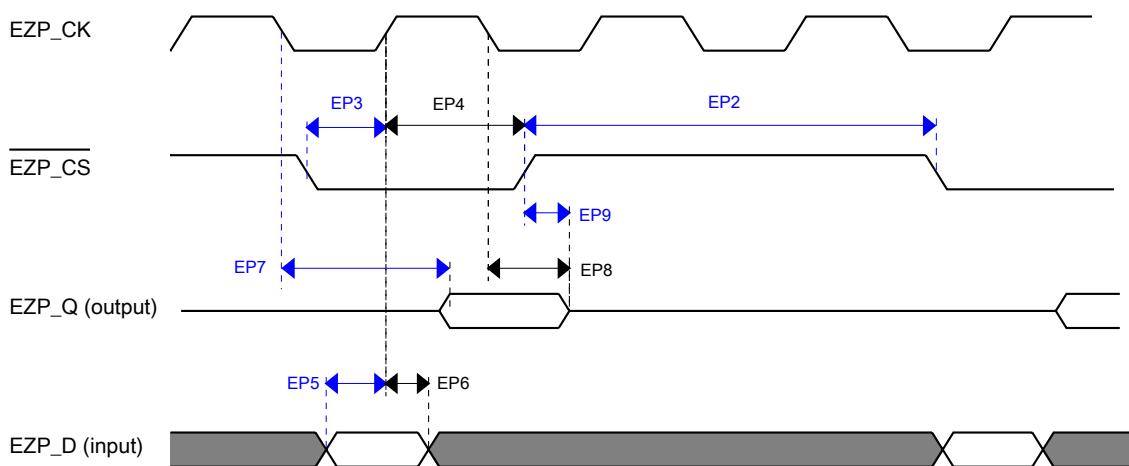
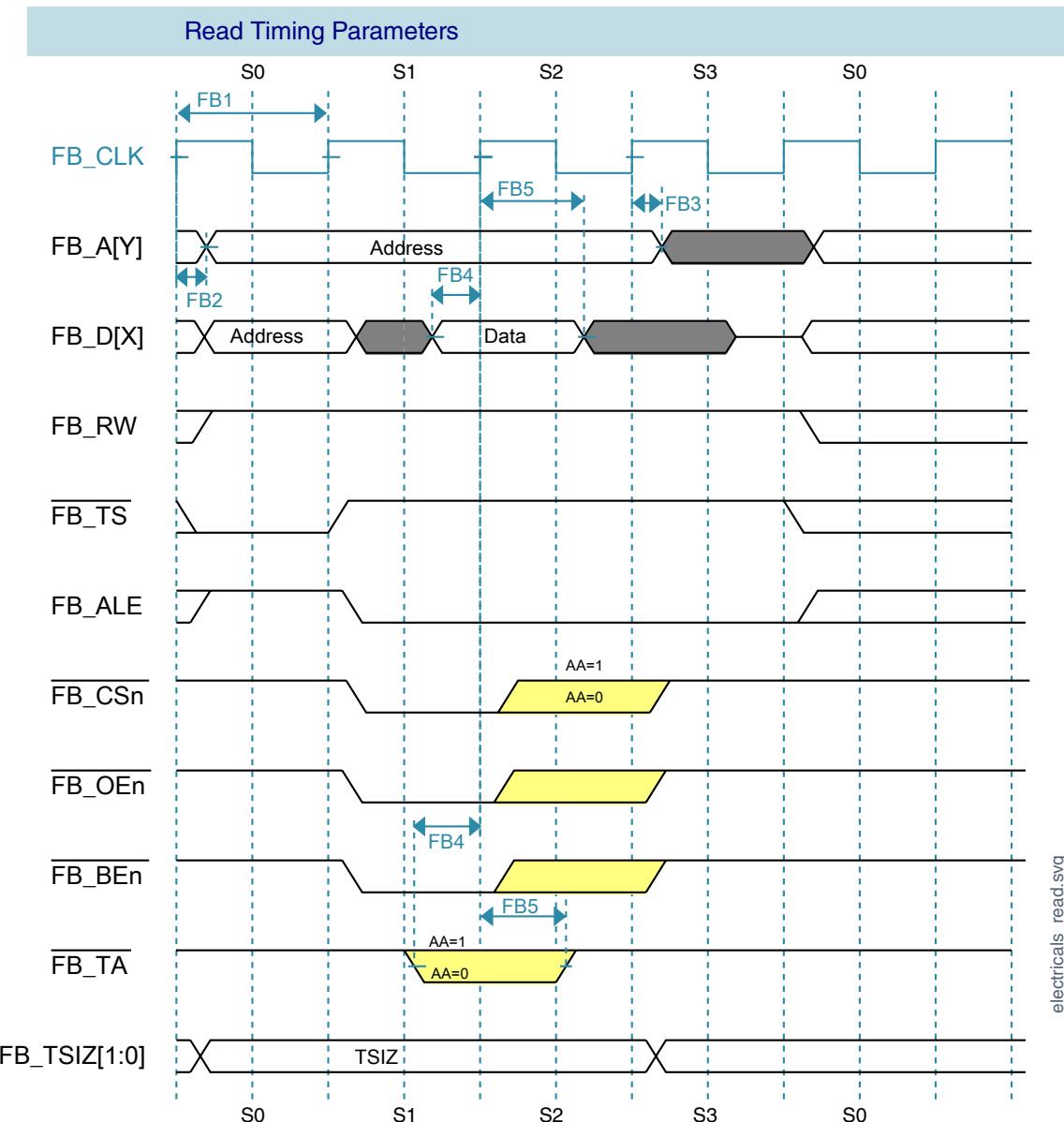


Figure 11. EzPort Timing Diagram

**Figure 12. FlexBus read timing diagram**

3.6.1 ADC electrical specifications

The 16-bit accuracy specifications listed in [Table 26](#) and [Table 27](#) are achievable on the differential pins ADCx_DP_x, ADCx_DM_x.

All other ADC channels meet the 13-bit differential/12-bit single-ended accuracy specifications.

3.6.1.1 16-bit ADC operating conditions

Table 26. 16-bit ADC operating conditions

Symbol	Description	Conditions	Min.	Typ. ¹	Max.	Unit	Notes
V _{DDA}	Supply voltage	Absolute	1.71	—	3.6	V	
ΔV _{DDA}	Supply voltage	Delta to V _{DD} (V _{DD} – V _{DDA})	-100	0	+100	mV	2
ΔV _{SSA}	Ground voltage	Delta to V _{SS} (V _{SS} – V _{SSA})	-100	0	+100	mV	2
V _{REFH}	ADC reference voltage high		1.13	V _{DDA}	V _{DDA}	V	
V _{REFL}	ADC reference voltage low		V _{SSA}	V _{SSA}	V _{SSA}	V	
V _{ADIN}	Input voltage	<ul style="list-style-type: none"> • 16-bit differential mode • All other modes 	V _{REFL} V _{REFL}	— —	31/32 * V _{REFH} V _{REFH}	V	
C _{ADIN}	Input capacitance	<ul style="list-style-type: none"> • 16-bit mode • 8-bit / 10-bit / 12-bit modes 	— —	8 4	10 5	pF	
R _{ADIN}	Input series resistance		—	2	5	kΩ	
R _{AS}	Analog source resistance (external)	13-bit / 12-bit modes f _{ADCK} < 4 MHz	—	—	5	kΩ	3
f _{ADCK}	ADC conversion clock frequency	≤ 13-bit mode	1.0	—	24.0	MHz	4
f _{ADCK}	ADC conversion clock frequency	16-bit mode	2.0	—	12.0	MHz	4
C _{rate}	ADC conversion rate	≤ 13-bit modes No ADC hardware averaging Continuous conversions enabled, subsequent conversion time	20	—	1200	Ksps	5
C _{rate}	ADC conversion rate	16-bit mode No ADC hardware averaging	37	—	461	Ksps	5

Table 27. 16-bit ADC characteristics ($V_{REFH} = V_{DDA}$, $V_{REFL} = V_{SSA}$) (continued)

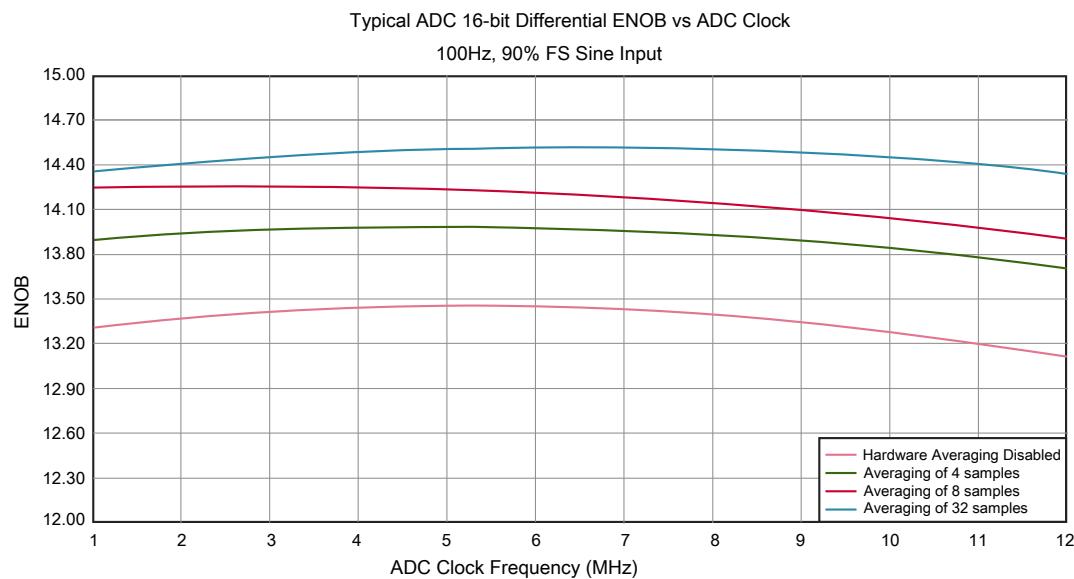
Symbol	Description	Conditions ¹	Min.	Typ. ²	Max.	Unit	Notes
f_{ADACK}	ADC asynchronous clock source	<ul style="list-style-type: none"> • ADLPC = 1, ADHSC = 0 • ADLPC = 1, ADHSC = 1 • ADLPC = 0, ADHSC = 0 • ADLPC = 0, ADHSC = 1 	1.2 2.4 3.0 4.4	2.4 4.0 5.2 6.2	3.9 6.1 7.3 9.5	MHz MHz MHz MHz	$t_{ADACK} = 1/f_{ADACK}$
	Sample Time	See Reference Manual chapter for sample times					
TUE	Total unadjusted error	<ul style="list-style-type: none"> • 12-bit modes • <12-bit modes 	— —	± 4 ± 1.4	± 6.8 ± 2.1	LSB ⁴	5
DNL	Differential non-linearity	<ul style="list-style-type: none"> • 12-bit modes • <12-bit modes 	— —	± 0.7 ± 0.2	-1.1 to +1.9 -0.3 to 0.5	LSB ⁴	5
INL	Integral non-linearity	<ul style="list-style-type: none"> • 12-bit modes • <12-bit modes 	— —	± 1.0 ± 0.5	-2.7 to +1.9 -0.7 to +0.5	LSB ⁴	5
E_{FS}	Full-scale error	<ul style="list-style-type: none"> • 12-bit modes • <12-bit modes 	— —	-4 -1.4	-5.4 -1.8	LSB ⁴	$V_{ADIN} = V_{DDA}$ ⁵
E_Q	Quantization error	<ul style="list-style-type: none"> • 16-bit modes • ≤13-bit modes 	— —	-1 to 0 —	— ± 0.5	LSB ⁴	
ENOB	Effective number of bits	16-bit differential mode <ul style="list-style-type: none"> • Avg = 32 • Avg = 4 16-bit single-ended mode <ul style="list-style-type: none"> • Avg = 32 • Avg = 4 	12.8 11.9 12.2 11.4	14.5 13.8 13.9 13.1	— — — —	bits bits bits bits	6
SINAD	Signal-to-noise plus distortion	See ENOB	$6.02 \times ENOB + 1.76$			dB	
THD	Total harmonic distortion	16-bit differential mode <ul style="list-style-type: none"> • Avg = 32 16-bit single-ended mode <ul style="list-style-type: none"> • Avg = 32 	— —	-94 -85	— —	dB dB	7
SFDR	Spurious free dynamic range	16-bit differential mode <ul style="list-style-type: none"> • Avg = 32 16-bit single-ended mode	82 78	95 90	— —	dB dB	7

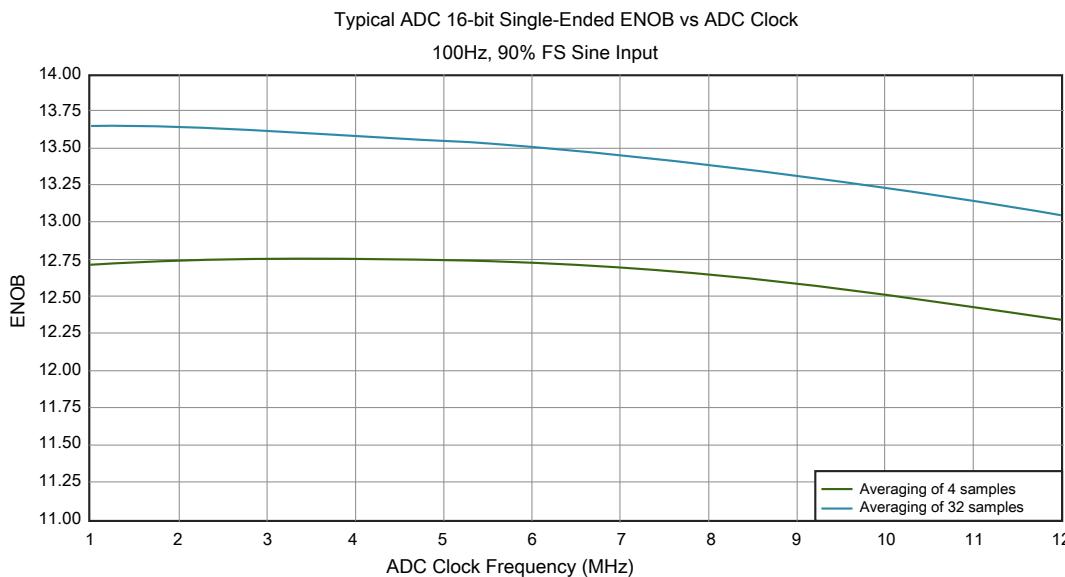
Table continues on the next page...

Table 27. 16-bit ADC characteristics ($V_{REFH} = V_{DDA}$, $V_{REFL} = V_{SSA}$) (continued)

Symbol	Description	Conditions ¹	Min.	Typ. ²	Max.	Unit	Notes
		• Avg = 32					
E_{IL}	Input leakage error			$I_{In} \times R_{AS}$		mV	I_{In} = leakage current (refer to the MCU's voltage and current operating ratings)
	Temp sensor slope	Across the full temperature range of the device	1.55	1.62	1.69	mV/°C	8
V_{TEMP25}	Temp sensor voltage	25 °C	706	716	726	mV	8

1. All accuracy numbers assume the ADC is calibrated with $V_{REFH} = V_{DDA}$
2. Typical values assume $V_{DDA} = 3.0$ V, Temp = 25 °C, $f_{ADCK} = 2.0$ MHz unless otherwise stated. Typical values are for reference only and are not tested in production.
3. The ADC supply current depends on the ADC conversion clock speed, conversion rate and ADC_CFG1[ADLPC] (low power). For lowest power operation, ADC_CFG1[ADLPC] must be set, the ADC_CFG2[ADHSC] bit must be clear with 1 MHz ADC conversion clock speed.
4. 1 LSB = $(V_{REFH} - V_{REFL})/2^N$
5. ADC conversion clock < 16 MHz, Max hardware averaging (AVGE = %1, AVGS = %11)
6. Input data is 100 Hz sine wave. ADC conversion clock < 12 MHz.
7. Input data is 1 kHz sine wave. ADC conversion clock < 12 MHz.
8. ADC conversion clock < 3 MHz

**Figure 15. Typical ENOB vs. ADC_CLK for 16-bit differential mode**

**Figure 16. Typical ENOB vs. ADC_CLK for 16-bit single-ended mode**

3.6.2 CMP and 6-bit DAC electrical specifications

Table 28. Comparator and 6-bit DAC electrical specifications

Symbol	Description	Min.	Typ.	Max.	Unit
V_{DD}	Supply voltage	1.71	—	3.6	V
I_{DDHS}	Supply current, High-speed mode (EN=1, PMODE=1)	—	—	200	μA
I_{DDLS}	Supply current, low-speed mode (EN=1, PMODE=0)	—	—	20	μA
V_{AIN}	Analog input voltage	$V_{SS} - 0.3$	—	V_{DD}	V
V_{AIO}	Analog input offset voltage	—	—	20	mV
V_H	Analog comparator hysteresis ¹ <ul style="list-style-type: none"> • CR0[HYSTCTR] = 00 • CR0[HYSTCTR] = 01 • CR0[HYSTCTR] = 10 • CR0[HYSTCTR] = 11 	—	5	—	mV
V_{CMPOh}	Output high	$V_{DD} - 0.5$	—	—	V
V_{CMPOl}	Output low	—	—	0.5	V
t_{DHS}	Propagation delay, high-speed mode (EN=1, PMODE=1)	20	50	200	ns
t_{DLS}	Propagation delay, low-speed mode (EN=1, PMODE=0)	80	250	600	ns
	Analog comparator initialization delay ²	—	—	40	μs
I_{DAC6b}	6-bit DAC current adder (enabled)	—	7	—	μA
INL	6-bit DAC integral non-linearity	-0.5	—	0.5	LSB ³
DNL	6-bit DAC differential non-linearity	-0.3	—	0.3	LSB

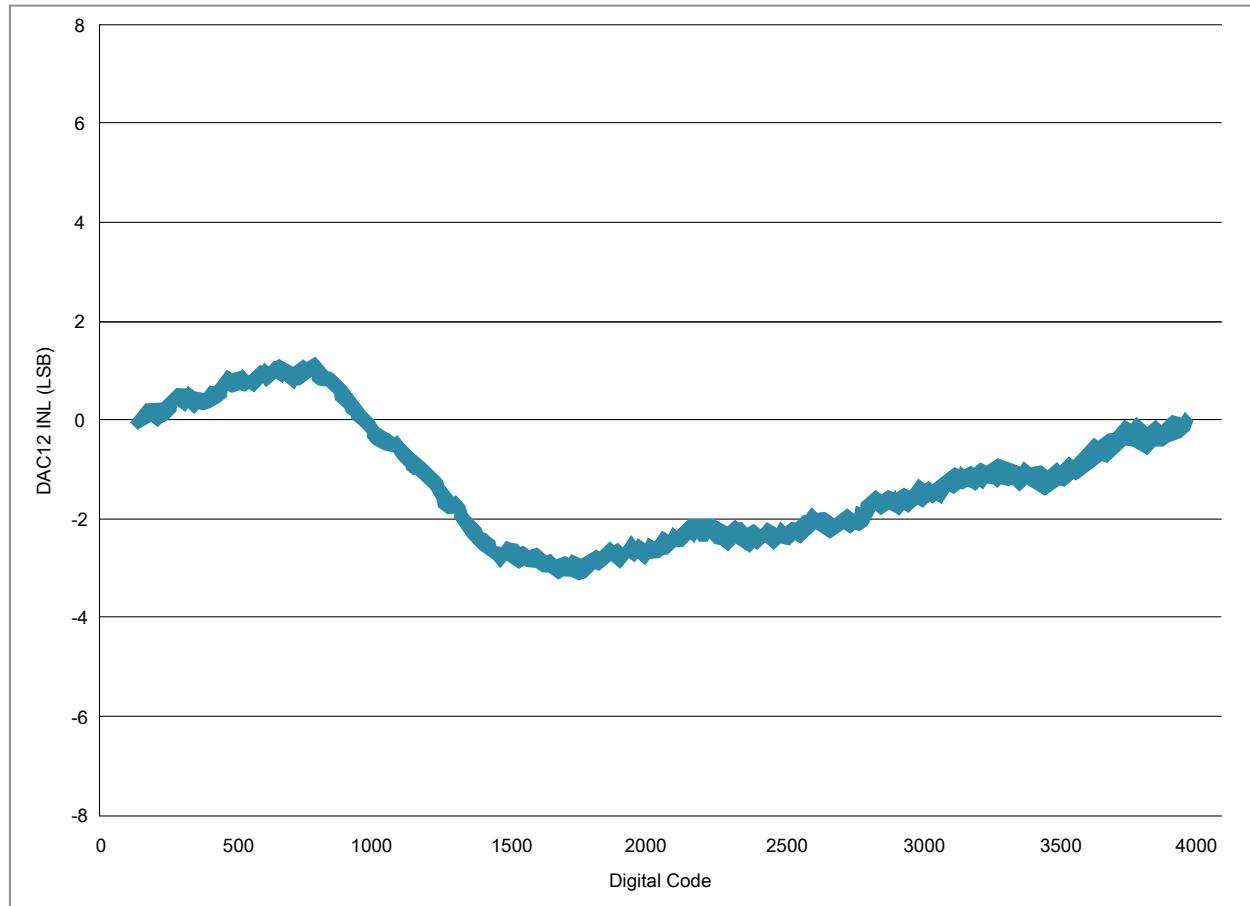
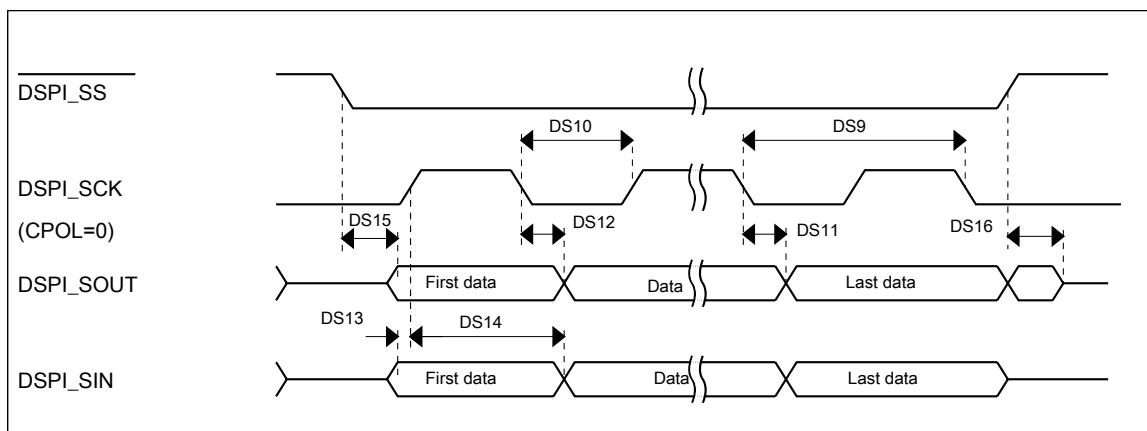


Figure 19. Typical INL error vs. digital code

Table 36. Slave mode DSPI timing (limited voltage range)

Num	Description	Min.	Max.	Unit	Notes
	Operating voltage	2.7	3.6	V	
	Frequency of operation	—	15	MHz	1
DS9	DSPI_SCK input cycle time	$4 \times t_{BUS}$	—	ns	
DS10	DSPI_SCK input high/low time	$(t_{SCK}/2) - 2$	$(t_{SCK}/2) + 2$	ns	
DS11	DSPI_SCK to DSPI_SOUT valid	—	21.4	ns	
DS12	DSPI_SCK to DSPI_SOUT invalid	0	—	ns	
DS13	DSPI_SIN to DSPI_SCK input setup	2.6	—	ns	
DS14	DSPI_SCK to DSPI_SIN input hold	7	—	ns	
DS15	DSPI_SS active to DSPI_SOUT driven	—	17	ns	
DS16	DSPI_SS inactive to DSPI_SOUT not driven	—	17	ns	

1. The maximum operating frequency is measured with noncontinuous CS and SCK. When DSPI is configured with continuous CS and SCK, the SPI clock must not be greater than 1/6 of the bus clock. For example, when the bus clock is 60 MHz, the SPI clock must not be greater than 10 MHz.

**Figure 22. DSPI classic SPI timing — slave mode**

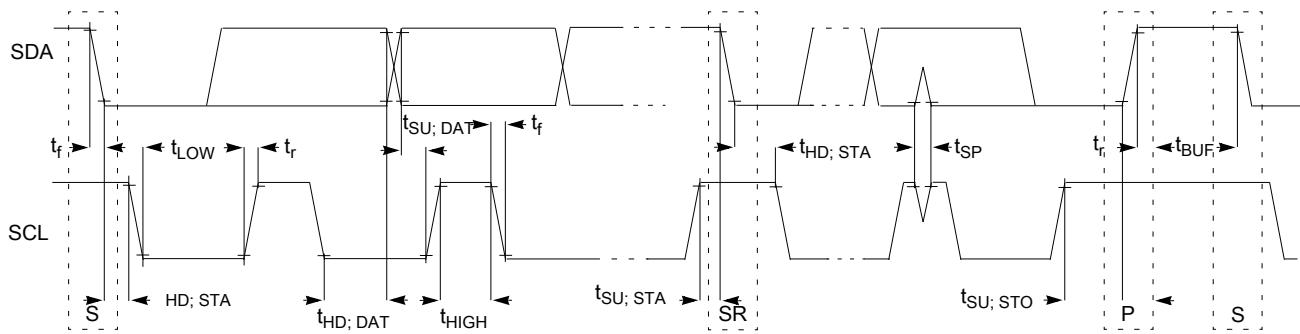


Figure 25. Timing definition for devices on the I²C bus

3.8.4 UART switching specifications

See [General switching specifications](#).

3.9 Kinetis Motor Suite

Kinetis Motor Suite is a bundled software solution that enables the rapid configuration of motor drive systems, and accelerates development of the final motor drive application.

Several members of the KV3x family are enabled with Kinetis motor suite. The enabled devices can be identified within the orderable part numbers in [this table](#). For more information refer to Kinetis Motor Suite User's Guide (KMS100UG) and Kinetis Motor Suite API Reference Manual (KMS100RM).

NOTE

To find the associated resource, go to [freescale.com](#) and perform a search using Document ID.

4 Dimensions

4.1 Obtaining package dimensions

Package dimensions are provided in package drawings.

To find a package drawing, go to [freescale.com](#) and perform a keyword search for the drawing's document number:

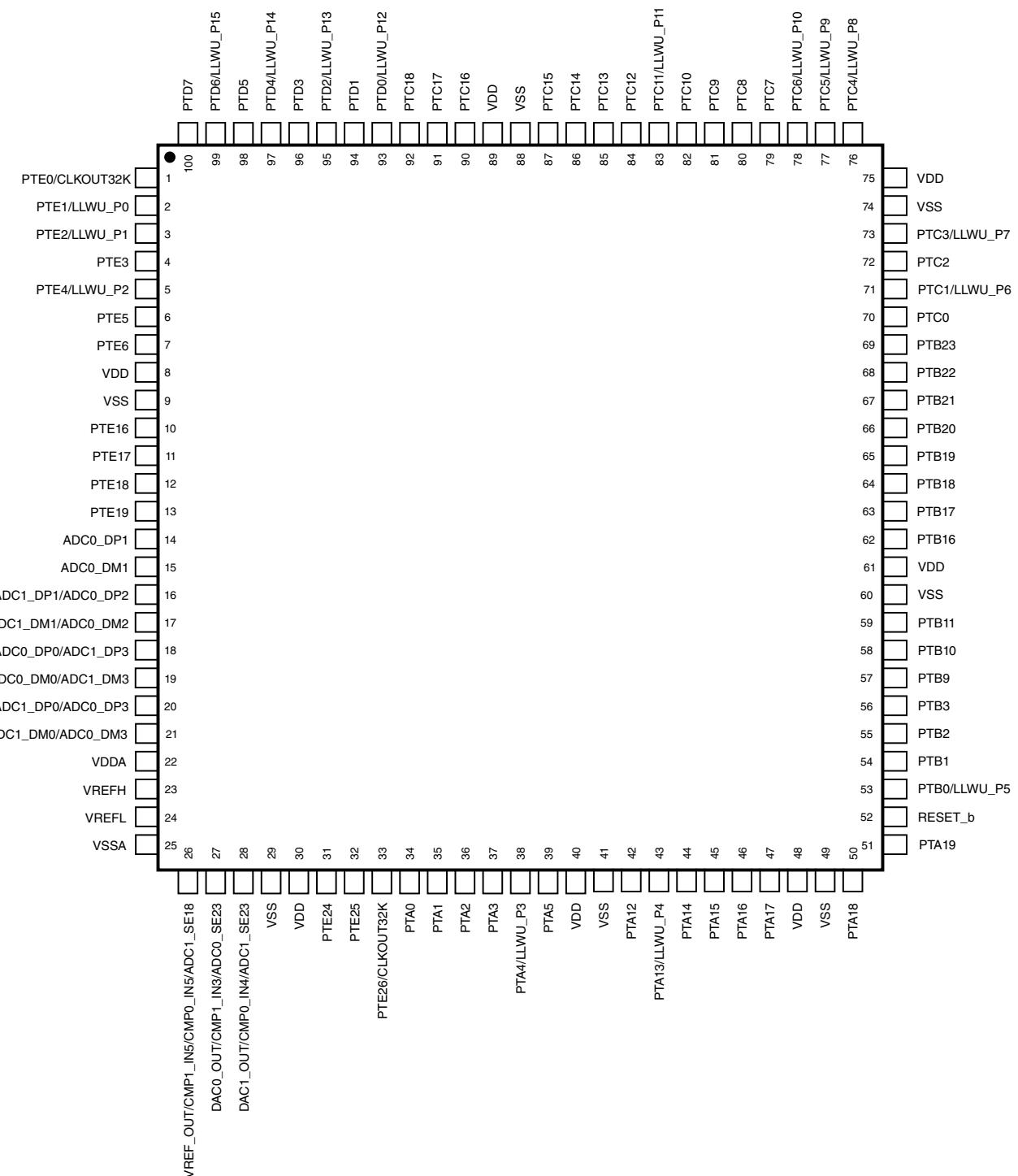


Figure 27. KV31F 100 LQFP Pinout Diagram (top view)

6 Part identification

6.1 Description

Part numbers for the chip have fields that identify the specific part. You can use the values of these fields to determine the specific part you have received.

6.2 Format

Part numbers for this device have the following format:

Q KV## A FFF R T PP CC S N

6.3 Fields

This table lists the possible values for each field in the part number (not all combinations are valid):

Field	Description	Values
Q	Qualification status	<ul style="list-style-type: none"> M = Fully qualified, general market flow P = Prequalification
KV##	Kinetis V Series	<ul style="list-style-type: none"> KV3x: Cortex-M4 based MCU
A	Key attribute	<ul style="list-style-type: none"> D = Cortex-M4 w/ DSP F = Cortex-M4 w/ DSP and FPU
FFF	Program flash memory size	<ul style="list-style-type: none"> 64 = 64 KB 128 = 128 KB 256 = 256 KB 512 = 512 KB
R	Silicon revision	<ul style="list-style-type: none"> (Blank) = Main A = Revision after main
T	Temperature range (°C)	<ul style="list-style-type: none"> V = -40 to 105 C = -40 to 85
PP	Package identifier	<ul style="list-style-type: none"> FM = 32 QFN (5 mm x 5 mm) LF = 48 LQFP (7 mm x 7 mm) LH = 64 LQFP (10 mm x 10 mm) LL = 100 LQFP (14 mm x 14 mm) MC = 121 XFBGA (8 mm x 8 mm) DC = 121 XFBGA (8 mm x 8 mm x 0.5 mm)
CC	Maximum CPU frequency (MHz)	<ul style="list-style-type: none"> 10 = 100 MHz 12 = 120 MHz
S	Software type	<ul style="list-style-type: none"> P = KMS-PMSM and BLDC (Blank) = Not software enabled
N	Packaging type	<ul style="list-style-type: none"> R = Tape and reel (Blank) = Trays